

## ABSTRACT OF THE DISCLOSURE

A semiconductor integrated circuit device including (a) an actual input circuit (03A, 04A), (b) an actual output circuit (05A, 06A), (c) a replica input circuit (12A) having the same characteristics as those of the actual input circuit, (d) a replica output circuit (11A) having the same characteristics as those of the actual input circuit, (e) an oscillating circuit (15A) which operates in accordance with external triggers, and (f) a skew-comparing circuit (10A) which compares a signal transmitted from the oscillating circuit and passing through the actual input circuit and the actual output circuit, to a signal transmitted from the oscillating circuit and passing through the replica input circuit and the replica output circuit to detect a delay error between the actual input and output circuits and the replica input and output circuits, wherein delays in the replica input and output circuits are compensated for in accordance with the delay error detected by the skew-comparing circuit.

Drawing to be published: FIG. 3